


<b>Search Notes</b>  	<b>Application/Control No.</b>  10572176	<b>Applicant(s)/Patent Under Reexamination</b>  WIEDEMANN ET AL.
	<b>Examiner</b>  SANG Y PAIK	<b>Art Unit</b>  3742

SEARCHED			
Class	Subclass	Date	Examiner
219	443.1-468.2,, 541-548	12/5/09	sp

SEARCH NOTES		
Search Notes	Date	Examiner
east searched	12/5/09	sp

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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